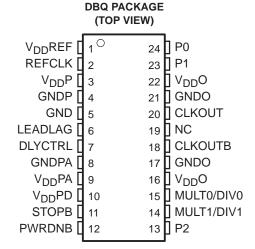
- Low Jitter Clock Multiplier by x4, x6, x8.
   Input Frequency Range (19 MHz to 125 MHz). Supports Output Frequency From 150 MHz to 500 MHz
- Fail-Safe Power Up Initialization
- Low Jitter Clock Divider by /2, /3, /4. Input Frequency Range (50 MHz to 125 MHz).
   Supports Ranges of Output Frequency From 12.5 MHz to 62.5 MHz
- 2.6 mUl Programmable Bidirectional Delay Steps
- Typical 8-ps Phase Jitter (12 kHz to 20 MHz) at 500 MHz
- Typical 2.1-ps RMS Period Jitter (Entire Frequency Band) at 500 MHz
- One Single-Ended Input and One Differential Output Pair
- Output Can Drive LVPECL, LVDS, and LVTTL
- Three Power Operating Modes to Minimize Power
- Low Power Consumption (Typical 200 mW at 500 MHz)
- Packaged in a Shrink Small-Outline Package (DBQ)
- No External Components Required for PLL
- Spread Spectrum Clock Tracking Ability to Reduce EMI

- Applications: Video Graphics, Gaming Products, Datacom, Telecom
- Accepts LVCMOS, LVTTL Inputs for REFCLK Terminal
- Accepts Other Single-Ended Signal Levels at REFCLK Terminal by Programming Proper V<sub>DD</sub>REF Voltage Level (For Example, HSTL 1.5 if V<sub>DD</sub>REF = 1.6 V)
- Supports Industrial Temperature Range of -40°C to 85°C



NC - No internal connection

### description

The CDC5801A device provides clock multiplication and division from a single-ended reference clock (REFCLK) to a differential output pair (CLKOUT/CLKOUTB). The multiply and divide terminals (MULT/DIV0:1) provide selection for frequency multiplication and division ratios, generating CLKOUT/CLOUTKB frequencies ranging from 12.5 MHz to 500 MHz with a clock input reference (REFCLK) ranging from 19 MHz to 125 MHz. See Table 1 and Table 2 for detail frequency support.

The implemented phase aligner provides the possibility to phase align (zero delay) between CLKOUT/CLKOUTB and REFCLK or any other CLK in the system by feeding the clocks that need to be aligned to the DLYCTRL and the LEADLAG terminals.

The phase aligner also allows the user to delay or advance the CLKOUT/CLKOUTB with steps of 2.6 mUI (unit interval). For every rising edge on the DLYCTRL terminal, the output clocks are delayed by 2.6-mUI step size as long as there is low on the LEADLAG terminal. Similarly, for every rising edge on the DLYCTRL terminal, the output clocks are advanced by 2.6-mUI step size as long as there is high on the LEADLAG terminal. The CDC5801A has a fail-safe power up initialization state-machine which supports proper operation under all power up conditions. As the phase between REFCLK and CLKOUT/CLKOUTB is random after power up, the application may implement a self calibration routine at power up to produce a certain phase start position, before programming a fixed delay with the clock on the DLYCTRL terminal.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



# CDC5801A LOW JITTER CLOCK MULTIPLIER AND DIVIDER WITH PROGRAMMABLE DELAY AND PHASE ALIGNMENT

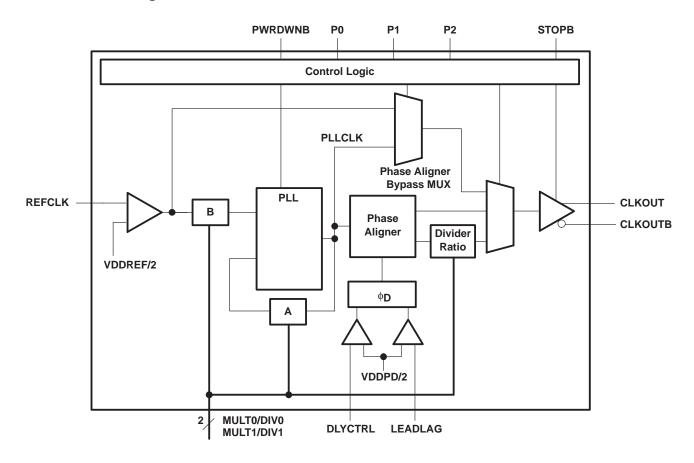
SCAS813A - AUGUST 2005 - REVISED DECEMBER 2005

Depending on the selection of the mode terminals (P0:2), the device behaves as a multiplier (by 4, 6, or 8) with the phase aligner bypassed or as a multiplier or divider with programmable delay and phase aligner functionality. Through the select terminals (P0:2) user can also bypass the phase aligner and the PLL (test mode) and output the REFCLK directly on the CLKOUT/CLKOUTB terminals. Through P0:2 terminals the outputs could be in a high impedance state. This device has another unique capability to be able to function with a wide band of voltages on the REFCLK terminal by varying the voltage on the VDDREF terminal.

The CDC5801A has a fail-safe power up initialization state-machine which supports proper operation under all power up conditions.

The CDC5801A device is characterized for operation over free-air temperatures of -40°C to 85°C.

### functional block diagram





# CDC5801A LOW JITTER CLOCK MULTIPLIER AND DIVIDER WITH PROGRAMMABLE DELAY AND PHASE ALIGNMENT

SCAS813A - AUGUST 2005 - REVISED DECEMBER 2005

### FUNCTION TABLET

MODE	P0	P1	P2	CLKOUT/CLKOUTB
Multiplication with programmable delay and phase alignment active <sup>‡</sup>	0	0	0	REFCLK multiplied by ratio per Table 1 selected by MULT/DIV terminals. Outputs are delayed or advanced based on DLYCTRL and LEADLAG terminal configuration.
Division with programmable delay and phase alignment active ‡	0	0	1	REFCLK divided by ratio per Table 2 selected by MULT/DIV terminals. Outputs are delayed or advanced based on DLYCTRL and LEADLAG terminal configuration.
Multiplication only mode (phase aligner bypassed) §	1	0	0	In this mode one can only multiply as per Table 1. Programmable delay capability and divider capability is deactivated. PLL is running.
Test mode	1	1	0	PLL and phase aligner both bypassed. REFCLK is directly channeled to output.
Hi-Z mode	0	1	Х	Hi-Z

<sup>†</sup>X = don't care, Hi-Z = high impedance

### **Terminal Functions**

TERMIN	IAL		
NAME	NO.	1/0	DESCRIPTION
CLKOUT	20	0	Output clock
CLKOUTB	18	0	Output clock (complement)
DLYCTRL	7	I	Every rising edge on this terminal delays/advances the CLKOUT/CLKOUTB signal by 1/384th of the CLKOUT/CLKOUTB period. (e.g., for a 90 degree delay or advancement one needs to provide 96 rising edges). See Table 4.
GND	5		GND for V <sub>DD</sub> REF and V <sub>DD</sub> PD
GNDO	17, 21		GND for clock output terminals (CLKOUT, CLKOUTB)
GNDP	4		GND for PLL
GNDPA	8		GND for phase aligner
LEADLAG	6	I	Decides if the output clock is delayed or advanced with respect to REFCLK. See Table 4.
MULT0/DIV0	15	I	PLL multiplier and divider select
MULT1/DIV1	14	I	PLL multiplier and divider select
NC	19		Not used
PWRDNB	12	I	Active low power down state, CLKOUT/CLKOUTB goes low
P0	24	I	Mode control, see the Function Table
P1	23	I	Mode control, see the Function Table
P2	13	I	Mode control, see the Function Table
REFCLK	2	I	Reference input clock
STOPB	11	I	Active low output disabler, PLL and PA still running, CLKOUT and CLKOUTB goes to a dc value as per Table 3
V <sub>DD</sub> PA	9	I	Supply voltage for phase aligner
V <sub>DD</sub> PD	10	I	Reference voltage for the DLYCTRL, LEADLAG terminals and STOPB function
V <sub>DD</sub> REF	1	I	Reference voltage for REFCLK
V <sub>DD</sub> O	16, 22	I	Supply voltage for the output terminals (CLKOUT, CLKOUTB)
$V_{DD}P$	3	I	Supply voltage for PLL

<sup>‡</sup> Please see Table 4 and Table 5 for explanation for the programmability and phase alignment functions.

<sup>§</sup> In this mode the DLYCTRL and LEADLAG terminals must be strapped high or low. Lowest possible jitter is achieved in this mode, but a delay of 200 ps to 2 ns expected typically from REFCLK to CLKOUT depending on the output frequency.

### PLL divider/multiplier selection

Table 1 and Table 2 list the supported REFCLK and BUSCLK (CLKOUT/CLKOUTB) frequencies.

Table 1. Multiplication Ratios (P0:2 = 000 or 100)

MULT0	MULT1	REFCLK (MHZ)	MULTIPLICATION RATIO	BUSCLK (MHZ)
0	0	38–125	4	152–500
0	1	25-83.3	6	150–500
1	1	19–62.5	8	152–500

Table 2. Divider Ratio (P0:2 = 001)

MULT0	MULT1	REFCLK (MHZ)	DIVISION RATIO	BUSCLK <sup>(1)</sup> (MHZ)
0	0	100–125	2	50-62.5
1	0	75–93	3	25–31
1	1	50-62	4	12.5–15.5

<sup>†</sup> BUSCLK will be undefined until a valid reference clock is available at REFCLK. After applying REFCLK, the PLL requires stabilization time to achieve phase lock.

**Table 3. Clock Output Driver States** 

STATE	PWRDNB	STOPB	CLKOUT	CLKOUTB
Powerdown	0	Х	GND	GND
CLK stop	1	0	VO, STOP	VO, STOP
Normal	1	1	As per Function Table	As per Function Table

**Table 4. Programmable Delay and Phase Alignment** 

DLYCTRL	LEADLAG	CLKOUT AND CLKOUTB
Each rising edge†	1	Will be advanced by one step size (see Table 5)
Each rising edge†	0	Will be delayed by one step size (see Table 5)

<sup>†</sup> For every 32<sup>nd</sup> edge, there are one or two edges the phase aligner does not update. Therefore, CLKOUT phase is not updated on every 32<sup>nd</sup> edge.

**Table 5. Clock Output Driver States** 

FUNCTIONALITY	STEP SIZE
Multiply by 4, 6, 8	CLKOUT period/384 (for example, 6.5 ps at 400 MHz)
Divide by 2	CLKOUT period/3072 (for example, 6.5 ps at 50 MHz)
Divide by 3	CLKOUT period/6144 (for example, 6.5 ps at 25 MHz)
Divide by 4	CLKOUT period/12288 (for example, 6.5 ps at 12.5 MHz)

NOTE: The frequency of the DLYCTRL terminal must always be equal or less than the frequency of the LEADLAG terminal.



# absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Supply voltage range, V <sub>DD</sub> (see Note 1)	0.5 V to 4 V
Output voltage range, V <sub>O</sub> , at any output terminal	0.5 V to V <sub>DD</sub> + 0.5 V
Input voltage range, V <sub>I</sub> , at any input terminal	0.5 V to V <sub>DD</sub> + 0.5 V
Continuous total power dissipation	see Dissipation Rating Table
Operating free-air temperature range, T <sub>A</sub>	–40°C to 85°C
Storage temperature range, T <sub>Stq</sub>	–65°C to 150°C
Lead temperature 1.6 mm (1/16 inch) from case for 10 seconds	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to the GND terminals.

### **DISSIPATION RATING TABLE**

PACKAGE	$T_{\mbox{\scriptsize A}} \le 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C <sup>‡</sup>	T <sub>A</sub> = 85°C POWER RATING
DBQ	1400 mW	11 mW/°C	740 mW

<sup>&</sup>lt;sup>‡</sup> This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.

### recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V <sub>DD</sub> (V <sub>DD</sub> P, V <sub>DD</sub> PA, V <sub>DD</sub> O)	3	3.3	3.6	V
High-level input voltage, V <sub>IH</sub> (CMOS)	$0.7 \times V_{DD}$			V
Low-level input voltage, V <sub>IL</sub> (CMOS)			$0.3 \times V_{DD}$	V
REFCLK low-level input voltage, V <sub>IL</sub>			$0.3 \times V_{DD}REF$	V
REFCLK high-level input voltage, VIH	$0.7 \times V_{DD}REF$			V
Input signal low voltage, V <sub>IL</sub> (STOPB, DLYCTRL, LEADLAG)			$0.3 \times V_{DD}PD$	V
Input signal high voltage, VIH (STOPB, DLYCTRL, LEADLAG)	$0.7 \times V_{DD}PD$			V
Input reference voltage for (REFCLK) (VDDREF)	1.235		$V_{DD}$	V
Input reference voltage for (DLYCTRL and LEADLAG) (VDDPD)	1.235		$V_{DD}$	V
High-level output current, IOH			-16	mA
Low-level output current, I <sub>OL</sub>			16	mA
Operating free-air temperature, T <sub>A</sub>	-40		85	°C

### timing requirements

	MIN	MAX	UNIT
Input frequency of modulation, f <sub>mod</sub> (if driven by SSC CLKIN)		33	kHz
Modulation index (nonlinear maximum 0.5%)		0.6%	
Input slew rate, SR	1	4	V/ns
Input duty cycle on REFCLK	40%	60%	
Input frequency on REFCLK	19	125	MHz
Allowable frequency on DLYCTRL		200	MHz
Allowable frequency on LEADLAG		400	MHz
Allowable duty cycle on DLYCTRL and LEADLAG	25%	75%	



# **CDC5801A** LOW JITTER CLOCK MULTIPLIER AND DIVIDER WITH PROGRAMMABLE DELAY AND PHASE ALIGNMENT

SCAS813A - AUGUST 2005 - REVISED DECEMBER 2005

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER			TEST CONI	DITIONS†	MIN	TYP‡	MAX	UNIT	
V <sub>O(STOP)</sub>	Output voltage during mode	g CLK stop	See Figure 1		1.1		2	V	
V <sub>OX</sub>	Output crossing-point voltage		See Figure 1 and Figure 4		0.5V <sub>DD</sub> O-0.2		0.5V <sub>DD</sub> O+0.2	V	
VO	Output voltage swing	J (VOH – VOL)	See Figure 1		1.7		2.9	V	
V <sub>IK</sub>	Input clamp voltage		V <sub>DD</sub> = 3 V,	I <sub>I</sub> = -18 mA			-1.2	V	
V	I Pale Level and and and		See Figure 1, V <sub>DD</sub>	= 3 to 3.6 V	2.0	2.6		.,	
VOH	High-level output voltage		V <sub>DD</sub> = 3 V,	I <sub>OH</sub> = -16 mA	2.2			V	
			See Figure 1, V <sub>DD</sub>	= 3 to 3.6 V		0.3	0.6	V	
VOL	Low-level output volt	age	$V_{DD} = 3 V$ ,	$I_{OL} = 16 \text{ mA}$			0.5	V	
			$V_{DD} = 3.135 V,$	V <sub>O</sub> = 1 V	-32	-52			
l <sub>OH</sub>	H High-level output current		$V_{DD} = 3.3 V$ ,	V <sub>O</sub> = 1.65 V		-51		mΑ	
			$V_{DD} = 3.465 V,$	V <sub>O</sub> = 3.135 V		-14.5	-21		
			$V_{DD} = 3.135 V,$	V <sub>O</sub> = 1.95 V	43	61.5			
loL	Low-level output current		V <sub>DD</sub> = 3.3 V,	V <sub>O</sub> = 1.65 V		65		mA	
			V <sub>DD</sub> = 3.465 V,	V <sub>O</sub> = 0.4 V		25.5	36		
I <sub>OZ</sub>	High-impedance-stat	High-impedance-state output current					±10	μА	
IOZ(STOP)	High-impedance-state output current during CLK stop		Stop = $0, V_O = GN$	ID or V <sub>DD</sub>			±100	μА	
I <sub>OZ(PD)</sub>	High-impedance-stat current in power-dow		PWRDNB = 0, $V_O$ = GND or $V_{DD}$		-10		100	μА	
		REFCLK, STOPB	V <sub>DD</sub> = 3.6 V,	$V_I = V_{DD}$			10		
lін	High-level input current	PWRDNB, P0:2, MULT/ DIV0:1	V <sub>DD</sub> = 3.6 V,	$V_I = V_{DD}$			10	μΑ	
	Lawlandiand	REFCLK, STOPB	V <sub>DD</sub> = 3.6 V,	V <sub>I</sub> = 0			-10		
I <sub>IL</sub>	Low-level input current	PWRDNB, P0:2, MULT/ DIV0:1	V <sub>DD</sub> = 3.6 V,	V <sub>I</sub> = 0			-10	μΑ	
_	Output impedance	High state	R <sub>I</sub> at I <sub>O</sub> –14.5 mA t	o –16.5 mA	15	35	50		
ZO	(single ended)	Low state	R <sub>I</sub> at I <sub>O</sub> 14.5 mA to	16.5 mA	11	17	35	Ω	
		V <sub>DD</sub> REF,		PWRDNB = 0			50	μΑ	
	Reference current	V <sub>DD</sub> PD	V <sub>DD</sub> = 3.6 V	PWRDNB = 1			0.5	mA	
Cl	Input capacitance		$V_I = V_{DD}$ or GND			2		pF	
СО	Output capacitance		$V_O = V_{DD}$ or GND			3		pF	
I <sub>DD(PD)</sub>	Supply current in pov	wer-down state	REFCLK = 0 MHz t PWDNB = 0,	o 100 MHz, STOPB = 1			150	μΑ	
IDD(CLKSTOP)	Supply current in CL	K stop state	BUSCLK configure	d for 500 MHz			40	mA	
I <sub>DD(NORMAL)</sub>	Supply current in nor	-	BUSCLK = 500 MH P0:2 = 000; load se	lz			70	mA	

<sup>†</sup>  $V_{DD}$  refers to any of the following;  $V_{DD}PA$ ,  $V_{DD}PD$ ,  $V_{DD}REF$ ,  $V_{DD}O$ , and  $V_{DD}P$  ‡ All typical values are at  $V_{DD}=3.3$  V,  $T_{A}=25^{\circ}C$ .



# jitter specification over recommended operating free-air temperature range and $V_{\mbox{\footnotesize{CC}}}$ (unless otherwise noted)

PARAMETER	CLKOUT	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	155 MHz	Period RMS (1 $\Sigma$ jitter, full frequency band) Period p-p Phase jitter (accumulated, 12 kHz to 20 MHz) Cycle-to-cycle (+) Cycle-to-cycle (-)		6 40 50 27 27		ps
	200 MHz	Period RMS (1Σ jitter, full frequency band) Period p-p Phase jitter (accumulated, 12 kHz to 20 MHz) Phase jitter (accumulated, 50 kHz to 80 MHz) Cycle-to-cycle (+) Cycle-to-cycle (-)		5.5 36 36 36 23 23		ps
<sup>t</sup> (jitter) (Multiplication only mode. Phase alignment and programmable delay features are not selected (PA bypass). See Figure 2.)	312 MHz	Period RMS (1 $\Sigma$ jitter, full frequency band) Period p-p Phase jitter (accumulated, 12 kHz to 20 MHz) Phase jitter (accumulated, 50 kHz to 80 MHz) Cycle-to-cycle (+) Cycle-to-cycle (-)		3 20 18 18 17 17		ps
	400 MHz	Period RMS (1 $\Sigma$ jitter, full frequency band) Period p-p Phase jitter (accumulated, 12 kHz to 20 MHz) Phase jitter (accumulated, 50 kHz to 80 MHz) Cycle-to-cycle (+) Cycle-to-cycle (-)		2.3 17 12 12 15 15		ps
	500 MHz	Period RMS (1Σ jitter, full frequency band) Period p-p Phase jitter (accumulated, 12 kHz to 20 MHz) Phase jitter (accumulated, 50 kHz to 80 MHz) Cycle-to-cycle (+) Cycle-to-cycle (-)		2.1 16 8 8 14 14		ps
	155 MHz	Period RMS (1Σ jitter, full frequency band) Period p-p Phase jitter (accumulated, 12 kHz to 20 MHz) Cycle-to-cycle (+) Cycle-to-cycle (-)		9 70 50 50 50		ps
<sup>t</sup> (jitter) (Multiplication with phase alignment and	200 MHz	Period RMS (1 $\Sigma$ jitter, full frequency band) Period p-p Phase jitter (accumulated, 12 kHz to 20 MHz) Phase jitter (accumulated, 50 kHz to 80 MHz) Cycle-to-cycle (+) Cycle-to-cycle (-)		7 55 36 36 40 40		ps
programmable delay features selected. See Figure 2.)	312 MHz	Period RMS (1 $\Sigma$ jitter, full frequency band) Period p-p Phase jitter (accumulated, 12 kHz to 20 MHz) Phase jitter (accumulated, 50 kHz to 80 MHz) Cycle-to-cycle (+) Cycle-to-cycle (-)		4 35 18 18 30 30		ps
	400 MHz	Period RMS (1 $\Sigma$ jitter, full frequency band) Period p-p Phase jitter (accumulated, 12 kHz to 20 MHz) Phase jitter (accumulated, 50 kHz to 80 MHz) Cycle-to-cycle (+) Cycle-to-cycle (-)		3.1 27 13 13 25 25		ps

<sup>†</sup> All typical values are at  $V_{DD} = 3.3 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .



# CDC5801A LOW JITTER CLOCK MULTIPLIER AND DIVIDER WITH PROGRAMMABLE DELAY AND PHASE ALIGNMENT SCAS813A – AUGUST 2005 – REVISED DECEMBER 2005

# jitter specification over recommended operating free-air temperature range and $V_{\mbox{\footnotesize{CC}}}$ (unless otherwise noted) (continued)

PARAMETE	R	CLKOUT	TEST CONDITIONS	MIN TYP†	MAX	UNIT
t(jitter) (Multiplication with phase alignment and programmable delay features selected. See Figure 2.)		500 MHz	Period RMS (1Σ jitter, full frequency band) Period p-p Phase jitter (accumulated, 12 kHz to 20 MHz) Phase jitter (accumulated, 50 kHz to 80 MHz) Cycle-to-cycle (+) Cycle-to-cycle (-)	2.9 24 9 9 20 20		ps
	MULT0:1 = 11 (Divider	12.5 MHz	Period RMS (1Σ jitter, full frequency band) Period p-p Cycle-to-cycle (+) Cycle-to-cycle (–)	12 75 55 55		ps
	ratio = 4)	15.5 MHz	Period RMS (1Σ jitter, full frequency band) Period p-p Cycle-to-cycle (+) Cycle-to-cycle (–)	8 50 38 38		ps
t(jitter) (Divider mode with phase aligner not active: DLYCTRL =LEADLAG = 0 or 1. See Figure 2.)	MULT0:1 = 10 (Divider	25 MHz	Period RMS (1Σ jitter, full frequency band) Period p-p Cycle-to-cycle (+) Cycle-to-cycle (-)	7.5 50 35 35		ps
	ratio = 3)	31 MHz	Period RMS (1Σ jitter, full frequency band) Period p-p Cycle-to-cycle (+) Cycle-to-cycle (–)	5.5 30 23 23		ps
	MULT0:1 = 00 (Divider ratio = 2)	50 MHz	Period RMS (1 $\Sigma$ jitter, full frequency band) Period p-p Phase jitter (accumulated, 12 kHz to 20 MHz) Cycle-to-cycle (+) Cycle-to-cycle (-)	8 40 12 30 30		ps
		62.5 MHz	Period RMS (1Σ jitter, full frequency band) Period p-p Phase jitter (accumulated, 12 kHz to 20 MHz) Cycle-to-cycle (+) Cycle-to-cycle (-)	5.5 28 9 24 24		ps
	MULTO:1 = 11	12.5 MHz	Period RMS (1 $\Sigma$ jitter, full frequency band) Period p-p Cycle-to-cycle (+) Cycle-to-cycle (-)	12.5 80 55 55		ps
t(jitter) (Divider mode with phase alignment and programmable delay features selected. See Figure 2.)	(Divider ratio = 4)	15.5 MHz	Period RMS (1 $\Sigma$ jitter, full frequency band) Period p-p Cycle-to-cycle (+) Cycle-to-cycle (-)	8.5 55 38 38		ps
	MULTO:1 = 10	25 MHz	Period RMS (1Σ jitter, full frequency band) Period p-p Cycle-to-cycle (+) Cycle-to-cycle (-)	10 60 35 35		ps
	(Divider ratio = 3)	31 MHz	Period RMS (1Σ jitter, full frequency band) Period p-p Cycle-to-cycle (+) Cycle-to-cycle (–)	7 40 23 23		ps



# jitter specification over recommended operating free-air temperature range and $V_{CC}$ (unless otherwise noted) (continued)

PARAMETE	PARAMETER CLKOUT TEST CONDITIONS			MIN	TYP†	MAX	UNIT
t(jitter) (Divider mode with phase alignment and	MULTO:1 = 00	50 MHz	Period RMS (1 $\Sigma$ jitter, full frequency band) Period p-p Phase jitter (accumulated, 12 kHz to 20 MHz) Cycle-to-cycle (+) Cycle-to-cycle (-)		9 50 13 35 35		ps
programmable delay features selected. See Figure 2.)	(Divider ratio = 2)	62.5 MHz	Period RMS (1Σ jitter, full frequency band) Period p-p Phase jitter (accumulated, 12 kHz to 20 MHz) Cycle-to-cycle (+) Cycle-to-cycle (–)		6.5 30 10 26 26		ps

<sup>†</sup> All typical values are at  $V_{DD} = 3.3 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

# switching characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYPT MAX	UNIT
t(DC)	Output duty cycle	See Figure 3	45%	55%	
t <sub>r</sub> , t <sub>f</sub>	Output rise and fall times (measured at 20%–80% of output voltage)	See Figure 5 and Figure 1	150	350	ps

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{DD}$  = 3.3 V,  $T_{A}$  = 25°C.



### state transition latency specifications

	PARAMETER			TEST CONDITIONS	MIN	түр†	MAX	UNIT
t(powerup)	Delay time, PWRDNB↑ to CLKOUT/ CLKOUTB output settled (excluding <sup>t</sup> (DISTLOCK))	Powerdown	Normal	See Figure 6			3	ms
(рологар)	Delay time, PWRDNB↑ to internal PLL and clock are on and settled			·			3	
	Delay time, power up to CLKOUT/CLKOUTB output settled	.,	NI	0			3	
<sup>t</sup> (VDDpowerup)	Delay time, power up to internal PLL and clock are on and settled	V <sub>DD</sub>	Normal	See Figure 6		3		ms
<sup>t</sup> (MULT)	MULT0 and MULT1 change to CLKOUT/ CLKOUTB output resettled (excluding <sup>t</sup> (DISTLOCK))	Normal	Normal	See Figure 7			1	ms
t(CLKON)	STOPB <sup>↑</sup> to CLKOUT/CLKOUTB glitch-free clock edges	CLK Stop	Normal	See Figure 8			10	ns
<sup>t</sup> (CLKSETL)	STOPB <sup>↑</sup> to CLKOUT/CLKOUTB output settled to within 50 ps of the phase before STOPB was disabled	CLK Stop	Normal	See Figure 8			20	cycles
<sup>t</sup> (CLKOFF)	STOPB↓ to CLKOUT/CLKOUTB output disabled	Normal	CLK Stop	See Figure 8			5	ns
t(powerdown)	Delay time, PWRDNB↓ to the device in the power-down mode	Normal	Power- down	See Figure 6	_	_	1	ms
<sup>t</sup> (STOP)	Maximum time in CLKSTOP (STOPB = 0) before reentering normal mode (STOPB = 1)	STOPB	Normal	See Figure 8			100	μs
<sup>t</sup> (ON)	Minimum time in normal mode (STOPB = 1) before reentering CLKSTOP (STOPB = 0)	Normal	CLK stop	See Figure 8	100			ms

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{DD} = 3.3 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

### PARAMETER MEASUREMENT INFORMATION

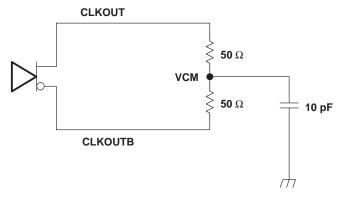


Figure 1. Test Load and Voltage Definitions ( $V_{O(STOP)}$ ,  $V_{OX}$ ,  $V_{OH}$ ,  $V_{OL}$ )



### PARAMETER MEASUREMENT INFORMATION

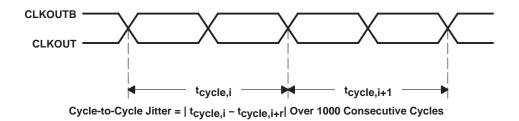


Figure 2. Cycle-to-Cycle Jitter

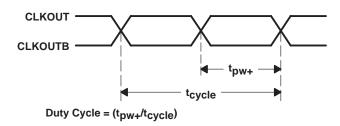


Figure 3. Output Duty Cycle

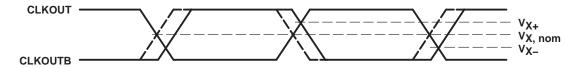
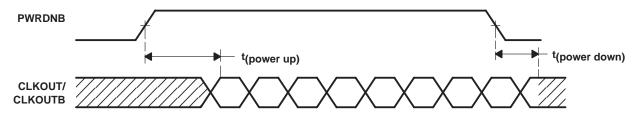


Figure 4. Crossing-Point Voltage



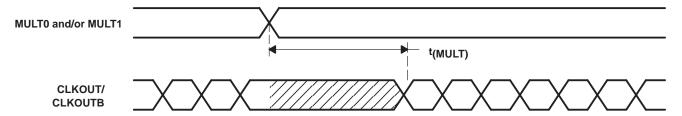
Figure 5. Voltage Waveforms



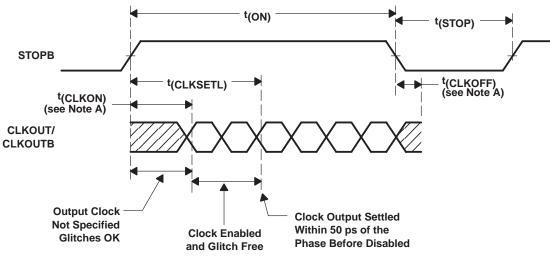
**Figure 6. PWRDNB Transition Timings** 



### PARAMETER MEASUREMENT INFORMATION



**Figure 7. MULT Transition Timings** 



NOTE A:  $V_{ref} = V_{O} \pm 200 \text{ mV}$ 

**Figure 8. STOPB Transition Timings** 



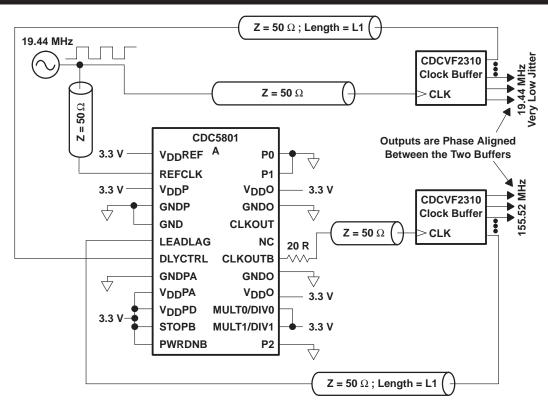


Figure 9. Using the CDC5801A Device as a Multiplier by 8 and Aligning Two Different Clocks

# PACKAGE MATERIALS INFORMATION

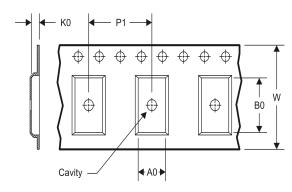
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## TAPE AND REEL INFORMATION

### **REEL DIMENSIONS**







A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### TAPE AND REEL INFORMATION

### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDC5801ADBQR	SSOP	DBQ	24	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1

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#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDC5801ADBQR	SSOP	DBQ	24	2500	367.0	367.0	38.0

DBQ (R-PDSO-G24)

## PLASTIC SMALL-OUTLINE PACKAGE



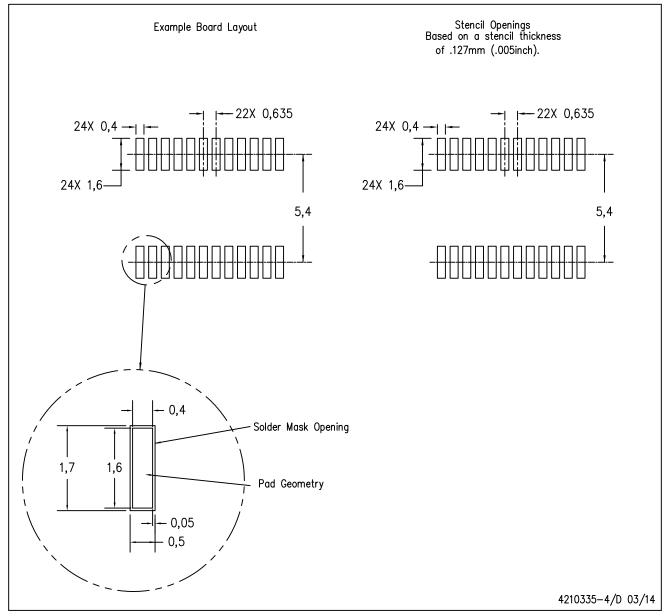
NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15) per side.
- D. Falls within JEDEC MO-137 variation AE.



DBQ (R-PDSO-G24)

# PLASTIC SMALL OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.



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